TO-220AB

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GDS

Top View



N-Channel 650 V (D-S) Super Junction MOSFET

PRODUCT SUMMA	RY			
V_{DS} (V) at T_{J} max.	650			
R _{DS(on)} max. (Ω) at 25 °C	$V_{GS} = 10 V$	0.19		
Q _g max. (nC)	106			
Q _{gs} (nC)	14			
Q _{gd} (nC)	33			
Configuration	Single			

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N-Channel MOSFET

FEATURES

- Reduced t_{rr}, Q_{rr}, and I_{RRM}
- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (Ciss)
- Low switching losses due to reduced Q_{rr}
- Ultra low gate charge (Q_a)
- Avalanche energy rated (UIS)

APPLICATIONS

- Telecommunications
- Server and telecom power supplies
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Consumer and computing - ATX power supplies
- Industrial
 - Welding
 - Battery chargers
- Renewable energy
- Solar (PV inverters)
- Switch mode power supplies (SMPS)

ABSOLUTE MAXIMUM RATINGS (T _C =	= 25 °C, unl	ess otherwis	se noted)		
PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage		V _{DS}	650	v	
Gate-Source Voltage		V _{GS}	± 30	V	
Continuous Drain Current (T 150 °C)	V _{GS} at 10 V	T _C = 25 °C T _C = 100 °C	1	20	
Continuous Drain Current (T _J = 150 °C)	V _{GS} at 10 V	T _C = 100 °C	Ι _D	13	А
Pulsed Drain Current ^a		I _{DM}	60		
Linear Derating Factor				1.7	W/°C
Single Pulse Avalanche Energy ^b			E _{AS}	367	mJ
Maximum Power Dissipation		P _D	208	W	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55 to +150	°C	
Drain-Source Voltage Slope	T _J = 1	25 °C	d\//dt	37 V/ns	
Reverse Diode dV/dt ^d		dV/dt	31	v/ns	
Soldering Recommendations (Peak Temperature) ^c	ecommendations (Peak Temperature) c for 10 s			300	°C

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b. $V_{DD} = 50$ V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 5.1 A.

c. 1.6 mm from case.

d. $I_{SD} \leq I_D$, dl/dt = 100 A/µs, starting T_J = 25 °C.





PARAMETER	SYMBOL	TYP.		MAX.			UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-		62				
Maximum Junction-to-Case (Drain)	R _{thJC}	-				°C/W		
SPECIFICATIONS ($T_J = 25 \ ^{\circ}C$, u	Inless otherw	ise noted)						
PARAMETER	SYMBOL		T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT
Static	•	•						<u> </u>
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	= 0 V, I _D =	250 µA	650	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C,	I _D = 1 mA	-	0.67	-	V/°C
Gate-Source Threshold Voltage (N)	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D =	250 µA	2	-	4	V
		$V_{GS} = \pm 20 \text{ V}$		V	-	-	± 100	nA
Gate-Source Leakage	I _{GSS}		$V_{GS} = \pm 30 \text{ V}$		-	-	± 1	V/°C V
Zero Gate Voltage Drain Current	1	V _{DS} =	V _{DS} = 520 V, V _{GS} = 0 V		-	-	1	μA
	IDSS	V _{DS} = 520 \	/, V _{GS} = 0 V, T _J = 125 °C		-	-	500	
Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = 10 V$		_D = 11 A	-	0.19	-	Ω
Forward Transconductance	9 _{fs}	V _{DS}	= 30 V, I _D :	= 11 A	-	7.0	-	S
Dynamic						-	-	
Input Capacitance	C _{iss}	V _{GS} = 0 V,		-	2322	-		
Output Capacitance	C _{oss}		$V_{DS} = 100$	V,	-	105	-	
Reverse Transfer Capacitance	C _{rss}		f = 1 MH:	<u>Z</u>	-	4	-	1
Effective Output Capacitance, Energy Related ^a	C _{o(er)}		(to 500 \/	V 0.V	-	84	-	pF
Effective Output Capacitance, Time Related ^b	C _{o(tr)}	$v_{\rm DS} = 0.0$	/ to 520 V,	v _{GS} = 0 v	-	293	-	
Total Gate Charge	Qg				-	71	106	
Gate-Source Charge	Q _{gs}	$V_{GS} = 10 \text{ V}$ $I_D = 11 \text{ A}, V_{DS} = 520 \text{ V}$		-	14	-	nC	
Gate-Drain Charge	Q _{gd}		1 [-	33	-	1
Turn-On Delay Time	t _{d(on)}				-	22	44	
Rise Time	t _r	$\label{eq:VDD} \begin{array}{l} V_{\text{DD}} = 520 \; V, \; I_{\text{D}} = 11 \; A, \\ V_{\text{GS}} = 10 \; V, \; R_{\text{g}} = 9.1 \; \Omega \end{array}$		-	34	68	- ns	
Turn-Off Delay Time	t _{d(off)}			-	68	102		
Fall Time	t _f]		-	42	84	
Gate Input Resistance	R _g	f = 1 MHz, open drain		-	0.78	-	Ω	
Drain-Source Body Diode Characteristi	cs							
Continuous Source-Drain Diode Current	I _S	MOSFET sym showing the	bol		-	-	21	^
Pulsed Diode Forward Current	I _{SM}	integral revers p - n junction			-	-	53	A
Diode Forward Voltage	V _{SD}	T _J = 25 °(C, I _S = 11 A	A, V _{GS} = 0 V	-	0.9	1.2	V
Reverse Recovery Time	t _{rr}				-	160	-	ns
Reverse Recovery Charge	Q _{rr}	T _J = 2	5 °C, $I_F = I_S$	s = 11 A,	-	1.2	-	μC
Reverse Recovery Current	I _{RRM}		100 A/µs,	v _R = 25 v	_	14	_	A

Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

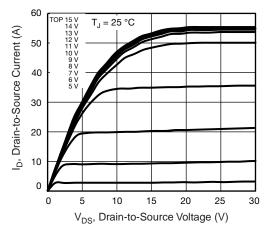


Fig. 1 - Typical Output Characteristics

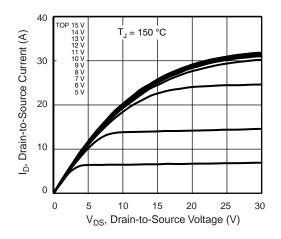


Fig. 2 - Typical Output Characteristics

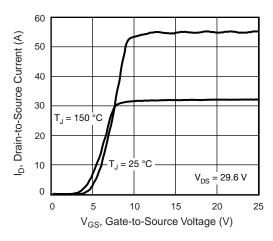


Fig. 3 - Typical Transfer Characteristics

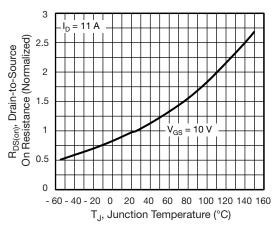


Fig. 4 - Normalized On-Resistance vs. Temperature

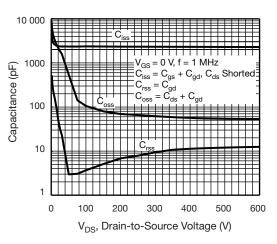


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

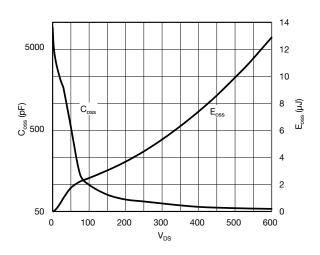


Fig. 6 - C_{oss} and E_{oss} vs. V_{DS}

STP20NM50FD



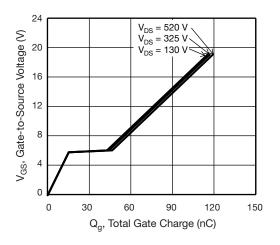


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

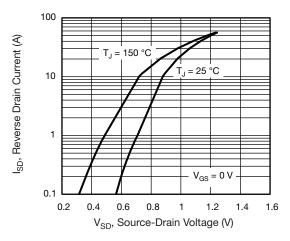


Fig. 8 - Typical Source-Drain Diode Forward Voltage

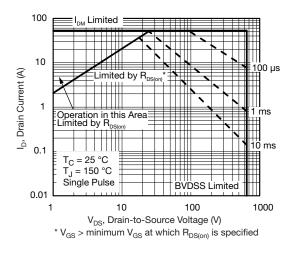


Fig. 9 - Maximum Safe Operating Area

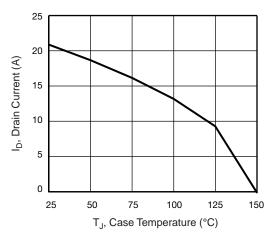


Fig. 10 - Maximum Drain Current vs. Case Temperature

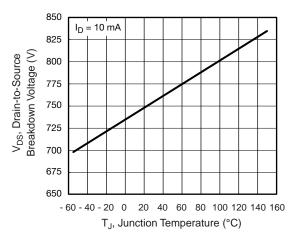


Fig. 11 - Temperature vs. Drain-to-Source Voltage



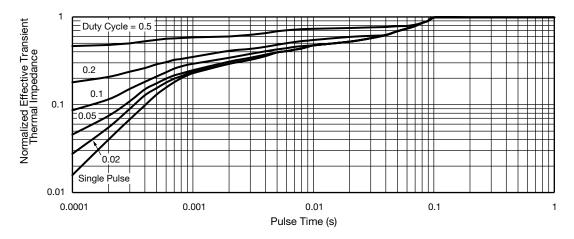


Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case

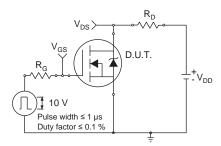


Fig. 13 - Switching Time Test Circuit

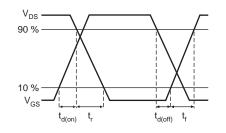


Fig. 14 - Switching Time Waveforms

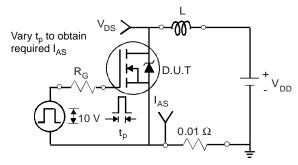


Fig. 15 - Unclamped Inductive Test Circuit

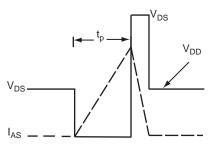


Fig. 16 - Unclamped Inductive Waveforms

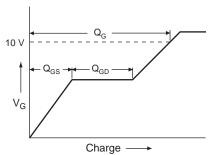
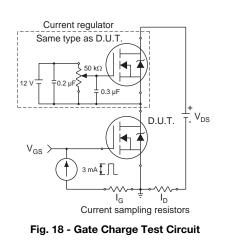
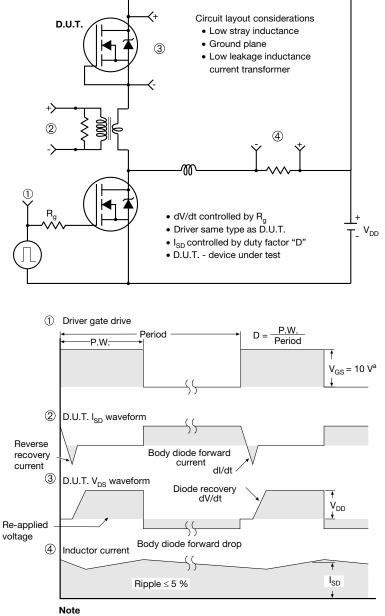


Fig. 17 - Basic Gate Charge Waveform





Peak Diode Recovery dV/dt Test Circuit

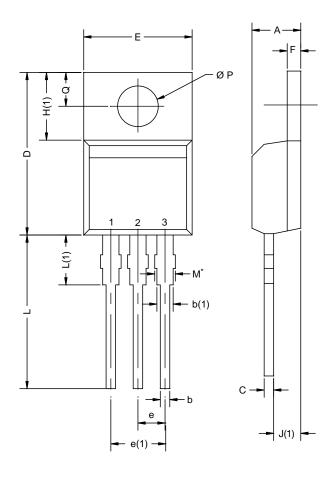


a. $V_{GS} = 5$ V for logic level devices

Fig. 19 - For N-Channel



TO-220AB



	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
с	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	

Notes

* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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